

**Notice of References Cited**

Application/Control No.

10/743,082

Applicant(s)/Patent Under

Reexamination

FURUKAWA, SHINJI

Examiner

Jason T. Whipkey

Art Unit

2622

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,151,421 A	11-2000	Yamada, Tomoko	382/284
*	B US-2003/0098915 A1	05-2003	Hyodo et al.	348/231.3
*	C US-6,937,234 B1	08-2005	Long, Timothy Merrick	348/745
*	D US-2005/0240627 A1	10-2005	Cohen et al.	707/104.1
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	JP 10084473 A	03-1998	Japan	IKEGAWA et al.	H04N 001/393
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.